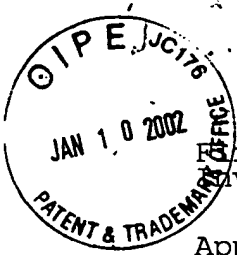


\$Receipt



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named Inventor : Matthew M. Johnston

Appln. No.: 09/917,363

Filed : July 27, 2001

For : TECHNIQUE FOR MEASURING SMALL DISTANCES BETWEEN AND FOR MEASURING THE FLATNESS OF, ELECTRICALLY CONDUCTIVE SURFACES

Docket No.: S01.12-0734

Group Art Unit: 2848

Examiner:

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JAN 24 2002
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REQUEST FOR CORRECTED FILING RECEIPT

Commissioner for Patents
Office of Initial Patent Examination
Customer Service Center
Washington, D.C. 20231

I HEREBY CERTIFY THAT THIS PAPER IS BEING SENT BY U.S. MAIL, FIRST CLASS, TO THE ASSISTANT COMMISSIONER FOR PATENTS, WASHINGTON, D.C. 20231, THIS

19 DAY OF October, 20 01.

A. Rego
PATENT ATTORNEY

Sir:

1. Enclosed is a copy of the Official Filing Receipt received from the PTO in the above-identified application for which issuance of a corrected Filing Receipt is requested along with a corrected File Data Sheet. Removal of the notation "Data inconsistent with PTO records" is respectfully requested.

2. There is an error with respect to the following data, which is incorrectly entered.

The correction for this error is indicated on the enclosed copy of the Official Filing Receipt and is listed below:

<u>Error in</u>	<u>Corrected data</u>
-----------------	-----------------------

- | | | | |
|----|--|----|--------------------|
| G. | [X] Priority Claim | G. | 60/221,532 7/28/00 |
| 3. | least one of the above corrections is due to applicant error and the fee therefor, under 37 C.F.R. § 1.19(h) \$25.00 is paid as follows: | | |

[X] Enclosed is a check for \$25.00

Repln. Ref: 01/16/2002 HND00R1 0008060800
Date: 231123 Name/Number: 09917363
FC: 704 \$25.00 CR

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The Director is authorized to charge any fee deficiency required by this paper or credit any overpayment to Deposit Account No. 23-1123. A duplicate copy of this communication is enclosed.

Respectfully submitted,

WESTMAN, CHAMPLIN & KELLY, P.A.

By: 

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APPLICATION NUMBER	FILING DATE	GRP ART UNIT	FIL FEE REC'D	ATTY. DOCKET NO	DRAWINGS	TOT CLAIMS	IND CLAIMS
09/917,363	07/27/2001	2878	790	S01.12- 0734/STL 9752	9	20	4

CONFIRMATION NO. 9874

FILING RECEIPT



OC000000006517302

Alan G. Rego
Westman, Champlin & Kelly
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Minneapolis, MN 55402-3319

Date Mailed: 09/06/2001

Receipt is acknowledged of this nonprovisional Patent Application. It will be considered in its order and you will be notified as to the results of the examination. Be sure to provide the U.S. APPLICATION NUMBER, FILING DATE, NAME OF APPLICANT, and TITLE OF INVENTION when inquiring about this application. Fees transmitted by check or draft are subject to collection. Please verify the accuracy of the data presented on this receipt. If an error is noted on this Filing Receipt, please write to the Office of Initial Patent Examination's Customer Service Center. Please provide a copy of this Filing Receipt with the changes noted thereon. If you received a "Notice to File Missing Parts" for this application, please submit any corrections to this Filing Receipt with your reply to the Notice. When the USPTO processes the reply to the Notice, the USPTO will generate another Filing Receipt incorporating the requested corrections (if appropriate).

Applicant(s)

Matthew M. Johnston, Edina, MN;

Domestic Priority data as claimed by applicant

THIS APPLN CLAIMS BENEFIT OF 60/221,532 07/28/2000 *

(*) Data inconsistent with PTO records.

Foreign Applications

If Required, Foreign Filing License Granted 09/05/2001

Projected Publication Date: 01/31/2002

Non-Publication Request: No

Early Publication Request: No

Title

Technique for measuring small distances between and for measuring the flatness of electrically conductive surfaces

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